

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Test methods for electrical materials, interconnection structures and assemblies –

Part 6: Test methods for materials used in manufacturing electronic assemblies

Méthodes d'essai pour les matériaux électriques, les structures d'interconnexion et les ensembles –

Partie 6: Méthodes d'essai des matériaux utilisés dans la fabrication des assemblages électroniques

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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland
Email: inmail@iec.ch
Web: www.iec.ch

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Fax: +41 22 919 03 00

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**Test methods for electrical materials, interconnection structures and assemblies –
Part 6: Test methods for materials used in manufacturing electronic assemblies**

**Méthodes d'essai pour les matériaux électriques, les structures d'interconnexion et les ensembles –
Partie 6: Méthodes d'essai des matériaux utilisés dans la fabrication des assemblages électroniques**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**TEST METHODS FOR ELECTRICAL MATERIALS,
INTERCONNECTION STRUCTURES AND ASSEMBLIES –**

**Part 6: Test methods for materials used
in manufacturing electronic assemblies**

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International Standard IEC 61189-6 has been prepared by IEC technical committee 91: Electronic assembly technology.

This bilingual version, published in 2008-05, corresponds to the English version.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/593/FDIS	91/610/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

The French version of this standard has not been voted upon.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This standard should be used in conjunction with the following parts of IEC 61189, under the main title *Test methods for electrical materials, interconnection structures and assemblies*:

Part 1: General test methods and methodology

Part 2: Test methods for materials for interconnection structures

Part 3: Test methods for interconnection structures (printed boards)

Part 4: Test methods for electronic components assembling characteristics (under consideration)

Part 5: Test methods for printed board assemblies

and also the following standard:

IEC 60068 series: Environmental testing

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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INTRODUCTION

IEC 61189 relates to test methods for printed boards and printed board assemblies, as well as related materials or component robustness, irrespective of their method of manufacture.

The IEC 61189 series is divided into separate parts, covering information for the designer and the test methodology engineer or technician. Each part has a specific focus; methods are grouped according to their application and numbered sequentially as they are developed and released.

In some instances test methods developed by other TCs (e.g. TC 104) have been reproduced from existing IEC standards in order to provide the reader with a comprehensive set of test methods. When this situation occurs, it will be noted on the specific test method; if the test method is reproduced with minor revision, those paragraphs that are different are identified.

This part of IEC 61189 contains test methods for evaluating materials used in manufacturing electronic assemblies. The methods are self-contained, with sufficient detail and description so as to achieve uniformity and reproducibility in the procedures and test methodologies.

The tests shown in this standard are grouped according to the following principles:

P: preparation/conditioning methods

V: visual test methods

D: dimensional test methods

C: chemical test methods

M: mechanical test methods

E: electrical test methods

N: environmental test methods

X: miscellaneous test methods

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To facilitate reference to the tests, to retain consistency of presentation, and to provide for future expansion, each test is identified by a number (assigned sequentially) added to the prefix (group code) letter showing the group to which the test method belongs.

The test method numbers have no significance with respect to an eventual test sequence; that responsibility rests with the relevant specification that calls for the method being performed. The relevant specification, in most instances, also describes pass/fail criterion.

The letter and number combinations are for reference purposes, to be used by the relevant specification. Thus "6C02" represents the second chemical test method described in this "Part 6" of IEC 61189. In this example, 6 is the part of IEC standard (61189-6), C is the group of methods, and 02 is the test number.

TEST METHODS FOR ELECTRICAL MATERIALS, INTERCONNECTION STRUCTURES AND ASSEMBLIES –

Part 6: Test methods for materials used in manufacturing electronic assemblies

1 Scope

This part of IEC 61189 is a catalogue of test methods representing methodologies and procedures that can be applied to materials used in manufacturing electronic assemblies.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*

IEC 61189-1, *Test methods for electrical materials, interconnection structures and assemblies – Part 1: General test methods and methodology*

IEC 61190-1-1, *Attachment materials for electronic assembly – Part 1-1: Requirements for soldering fluxes for high-quality interconnections in electronics assembly*

IEC 61190-1-3, *Attachment materials for electronic assembly – Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solders for electronic soldering applications*

ISO 9001, *Quality management systems – Requirements*

ISO 9455 (all parts), *Soft soldering fluxes – Test methods*

3 Accuracy, precision and resolution

Errors and uncertainties are inherent in all measurement processes. The information given below enables valid estimates of the amount of error and uncertainty to be taken into account.

Test data serve a number of purposes which include:

- monitoring a process;
- enhancing confidence in quality conformance;
- arbitrating between customer and supplier.

In any of these circumstances, it is essential that confidence can be placed upon the test data in terms of

- accuracy; calibration of the test instruments and/or system,
- precision; the repeatability and uncertainty of the measurement,
- resolution; the suitability of the test instrument and/or system.

3.1 Accuracy

The regime by which routine calibration of the test equipment is undertaken shall be clearly stated in the quality documentation of the supplier or agency conducting the test, and shall meet the requirements of ISO 9001.

The calibration shall be conducted by an agency having accreditation to a national or international measurement standard institute. There should be an uninterrupted chain of calibration to a national or international standard.

Where calibration to a national or international standard is not possible, "round robin" techniques may be used and documented to enhance confidence in measurement accuracy.

The calibration interval shall normally be one year. Equipment consistently found to be outside acceptable limits of accuracy shall be subject to shortened calibration intervals. Equipment consistently found to be well within acceptable limits may be subject to relaxed calibration intervals.

A record of the calibration and maintenance history shall be maintained for each instrument. These records should state the uncertainty of the calibration technique (in \pm % deviation) in order that uncertainties of measurement can be aggregated and determined.

A procedure shall be implemented to resolve any situation where an instrument is found to be outside calibration limits.

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3.2 Precision

The uncertainty budget of any measurement technique is made up of both systematic and random uncertainties. All estimates shall be based upon a single confidence level, the minimum being 95 % <https://standards.iteh.ai/catalog/standards/sist/f0931773-999e-4082-a687-1fc45904bfc0/iec-61189-6-2006>

Systematic uncertainties are usually the predominant contributor, and will include all uncertainties not subject to random fluctuation. These include:

- calibration uncertainties;
- errors due to the use of an instrument under conditions which differ from those under which it was calibrated;
- errors in the graduation of a scale of an analogue meter (scale shape error).

Random uncertainties result from numerous sources but can be deduced from repeated measurement of a standard item. Therefore, it is not necessary to isolate the individual contributions. These may include:

- random fluctuations such as those due to the variation of an influence parameter. Typically, changes in atmospheric conditions reduce the repeatability of a measurement;
- uncertainty in discrimination, such as setting a pointer to a fiducial mark, or interpolating between graduations on an analogue scale.

Aggregation of uncertainties: geometric addition (root-sum-square) of uncertainties may be used in most cases. Interpolation error is normally added separately and may be accepted as being 20 % of the difference between the finest graduations of the scale of the instrument:

$$U_t = \pm \sqrt{(U_s^2 + U_r^2)} + U_i$$

where

U_t is the total uncertainty;

U_s is the systematic uncertainty;

U_r is the random uncertainty;

U_i is the interpolation error.

Determination of random uncertainties: random uncertainty can be determined by repeated measurement of a parameter, and subsequent statistical manipulation of the measured data. The technique assumes that the data exhibits a normal (Gaussian) distribution:

$$U_r = \frac{t \times \sigma}{\sqrt{n}}$$

where

U_r is random uncertainty;

n is the specimen size;

t is the percentage point of the "t" distribution from 3.5, statistical tables;

σ is the standard deviation (σ_{n-1}).

3.3 Resolution

It is paramount that the test equipment used is capable of sufficient resolution. Measurement systems used should be capable of resolving 10 % (or better) of the test limit tolerance.

It is accepted that some technologies will place a physical limitation upon resolution (e.g. optical resolution).

3.4 Report

In addition to requirements detailed in the test specification, the report shall detail:

- a) the test method used;
- b) the identity of the specimen(s);
- c) the test instrumentation;
- d) the specified limit(s);
- e) an estimate of measurement uncertainty, and resultant working limit(s) for the test;
- f) the detailed test results;
- g) the test date, and operators' signature.

3.5 Student's "t" distribution

Table 1 gives values of the factor "t" for 95 % and 99 % confidence levels, as a function of the number of measurements. It is sufficient to use a 95 % limit, as in the case of the worked examples shown in Annex A of IEC 61189-1.

Table 1 – Student's "t" distribution

Specimen size	t value 95 %	t value 99 %	Specimen size	t value 95 %	t value 99 %
2	12,7	63,7	14	2,16	3,01
3	4,3	9,92	15	2,14	2,98
4	3,18	5,84	16	2,13	2,95
5	2,78	4,6	17	2,12	2,92
6	2,57	4,03	18	2,11	2,9
7	2,45	3,71	19	2,1	2,88
8	2,36	3,5	20	2,09	2,86
9	2,31	3,36	21	2,08	2,83
10	2,26	3,25	22	2,075	2,82
11	2,23	3,17	23	2,07	2,81
12	2,2	3,11	24	2,065	2,8
13	2,18	3,05	25	2,06	2,79

3.6 Suggested uncertainty limits

The following target uncertainties are suggested:

- a) voltage <1 kV: $\pm 1,5 \%$
- b) voltage >1 kV: $\pm 2,5 \%$
- c) current <20 A: $\pm 1,5 \%$
- d) current >20 A: $\pm 2,5 \%$

Resistance

- e) earth and continuity: $\pm 10 \%$
- f) insulation: $\pm 10 \%$
- g) frequency: $\pm 0,2 \%$

Time

- h) interval <60 s: $\pm 1 \text{ s}$
- i) interval >60 s: $\pm 2 \%$
- j) mass <10 g: $\pm 0,5 \%$
- k) mass (10 – 100) g: $\pm 1 \%$
- l) mass >100 g: $\pm 2 \%$
- m) force: $\pm 2 \%$
- n) dimension <25 mm: $\pm 0,5 \%$
- o) dimension >25 mm: $\pm 0,1 \text{ mm}$
- p) temperature <100 °C: $\pm 1,5 \%$
- q) temperature >100 °C: $\pm 3,5 \%$
- r) humidity (30 – 75) % RH: $\pm 5 \%$ RH

Plating thicknesses

- s) backscatter method: $\pm 10\%$
- t) microsection: ± 2 microns
- u) ionic contamination: $\pm 10\%$

4 Catalogue of approved test methods

This standard provides specific test methods in complete detail to permit implementation with minimal cross-referencing to other specific procedures. The use of generic conditioning exposures is accomplished in the methods by reference, for example those described in IEC 61189-1 and IEC 60068-1 and, when applicable, is a mandatory part of the test method standard.

Each method has its own title, number and revision status to accommodate updating and improving the methods as industry requirements change or demand new methodology. The methods are organized into test method groups and individual tests.

5 P: Preparation/conditioning test methods

Under consideration.

6 V: Visual test methods

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Under consideration.

7 D: Dimensional test methods

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Under consideration.

8 C: Chemical test methods

8.1 Test 6C01: Determination of acid value of liquid soldering flux – Potentiometric and visual titration methods

8.1.1 Object

This test method specifies two methods for the determination of the acid value of a flux of types L, M or H.

Method A is a potentiometric titration method and is to be considered as the reference method.

Method B is an alternative, visual end-point, titration method.

See ISO 9455 for reference.

8.1.2 Test specimen

A minimum of 2,0 g of liquid flux, 10 g of solder paste, 150 g of cored wire or 10 g of solder preforms.

8.1.3 Apparatus and reagents

8.1.3.1 General

- a) Use only reagents of recognized analytical quality and only distilled or deionized water.
- b) Ordinary laboratory apparatus.
- c) The term “M” represents molarity of a solution and is calculated by taking the moles of solute and dividing by the litres of solution, i.e. 1,00 mole of sucrose (about 342,3 g) mixed into a litre of water equals 1,00 M (1,00 mol/l).

8.1.3.2 Potentiometric titration method (Method A)

- a) Tetrabutyl ammonium hydroxide. 0,1 M (0,1 mol/l). Use a commercially available standard solution or one prepared from a commercially available concentrated standard solution by dilution with propan-2-ol. Standardize this solution against an accurately weighed amount of benzoic acid (about 0,5 g) dissolved in dimethylformamide, previously neutralized to thymol blue.
- b) Propan-2-ol: neutralized with tetrabutyl ammonium hydroxide solution to a faint pink colour using phenolphthalein as an indicator.
- c) Ethanol 96% by volume: neutralized with tetrabutyl ammonium hydroxide solution to a faint pink colour using phenolphthalein as an indicator.
- d) Toluene: neutralized with tetrabutyl ammonium hydroxide solution to a faint pink colour using phenolphthalein as an indicator.
- e) Ethanol/toluene mixture: mix equal volumes of the ethanol 96 % by volume and toluene.
- f) Millivoltmeter or pH meter. (standards.iteh.ai)
- g) Glass electrode.
- h) Saturated calomel, or silver chloride/silver electrode.
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- i) Magnetic or mechanical stirrer with variable speed drive.

8.1.3.3 Titration with visual end-point (Method B)

- a) Ethanol 96 % by volume: neutralized with potassium hydroxide, 0,1 M in alcohol, to a faint pink colour using phenolphthalein as an indicator.
- b) Toluene: neutralized with potassium hydroxide, 0,1 M in alcohol, to a faint pink colour using phenolphthalein as an indicator.
- c) Ethanol/toluene mixture: mix equal volumes of the ethanol 96 % by volume and toluene.
- d) Propan-2-ol: neutralized with potassium hydroxide, 0,1 M in alcohol, to a faint pink colour using phenolphthalein as an indicator.
- e) Potassium hydroxide solution: 0,1 M in alcohol. Use a commercially available standard solution or one prepared from a commercially available concentrated standard solution by dilution with ethanol. Standardize this solution against an accurately weighed amount of benzoic acid (about 0,5 g) dissolved in ethanol.
- f) Phenolphthalein indicator solution: Add 1 g of phenolphthalein to approximately 50 ml methanol and mix. When dissolved, dilute to 100 ml with methanol and mix.

8.1.4 Procedures

8.1.4.1 Potentiometric titration (Method A)

- a) By preliminary experiments, determine whether the specimen is soluble in propan-2-ol, ethanol 96 % by volume, toluene or the ethanol/toluene mixture. If it is not completely soluble in any of these solvents, select the one in which it appears to be the most soluble. If it is equally soluble in all four solvents then use propan-2-ol.

- b) Carry out the following procedure, in triplicate, on the flux specimen.
- c) Weigh, to the nearest 0,001 g, 2,0 g to 5,0 g of the liquid flux specimen taking steps to prevent loss of volatile matter during the weighing. The larger size specimen is required for very low solids fluxes. Transfer the weighed specimen to a 250 ml low form beaker.
- d) Dilute specimen to 100 ml with propan-2-ol, or the selected solvent, according to the solubility characteristics of the flux. Cover with a watch glass and dissolve the flux by gentle agitation.
- e) Place the beaker on the stand of the titration assembly with the electrodes, stirrer and burette in position. Adjust the speed of the stirrer to give vigorous stirring without splashing. Titrate with the tetrabutyl ammonium hydroxide solution, adding 1 ml portions and recording the pH, or mV meter readings after each addition. As the end point is approached, reduce the additions of titrant to 0,1 ml and continue titrating past the end point.
- f) Plot the pH, or potential values against the volume of titrant added to obtain the titration curve. The point of inflection of the curve corresponds to the end-point of the titration.
- g) Carry out a blank determination, using all reagents, for comparison purposes.

8.1.4.2 Visual titration (Method B)

- a) By preliminary experiments, determine whether the specimen is soluble in propan-2-ol, ethanol 96 % by volume, toluene or the ethanol/toluene mixture. If it is not completely soluble in any of these solvents, select the one in which it appears to be the most soluble. If it is equally soluble in all four solvents then use ethanol as the selected solvent.
- b) Carry out the following procedure, in triplicate, on the flux specimen.
- c) Weigh, to the nearest 0,001 g sufficient of the flux specimen to correspond to approximately 1 g of non-volatile matter in accordance with test method 6C03, taking steps in the case of liquid flux specimens to prevent loss of volatile matter during the weighing. <https://standards.iteh.ai/catalog/standards/sist/0931773-999e-4082-a687-16450045f60/iec-61189-6-2006>
- d) Transfer the weighed specimen to a suitable flask or beaker and add 100 ml of the selected solvent. Stir until the specimen has dissolved as completely as possible. Do not heat.
- e) Add 3 drops of phenolphthalein indicator and titrate with the potassium hydroxide (8.1.3.3) until a faint pink colour persists throughout the titrated solution for 15 s.
- f) Carry out blank determination, using all reagents, for comparison purposes.

8.1.4.3 Calculation of results

- a) The acid value is expressed in milligrams of potassium hydroxide per gram of non-volatile matter, regardless of the alkali used to perform the titration.
- b) The acid value (expressed in milligrams of potassium hydroxide per gram of non-volatile matter) is given by:

$$\frac{56,11VM}{mS}$$

where

V is the volume, in ml, of alkali used (tetrabutyl ammonium hydroxide for method A, potassium hydroxide for method B);

M is the molarity of the alkali used;

m is the mass, in grams of the specimen taken;

S is the percentage non-volatile matter determined as described in test method 6C03 of this standard.